

# Author details

[Back to results](#) | 1 of 1

[Print](#) | [E-mail](#)
**Larcher, Luca**

 Università degli Studi di Modena e Reggio Emilia,  
Modena, Italy

Author ID: 6603668511

<http://orcid.org/0000-0002-9139-349X>
[About Scopus Author Identifier](#) | [View potential author matches](#)

Other name formats: Larcher, L.

Documents: 204  
 Citations: 2819 total citations by 1848 documents  
 h-index: 29  
 Co-authors: 150 (maximum 150 co-authors can be displayed)  
 Subject area: Engineering , Materials Science [View More](#)

[Analyze author output](#)
[View citation overview](#)
[View h-graph](#)
**204 Documents** | Cited by 1848 documents | 150 co-authors

**204 documents** [View all in search results format](#)

 Sort on: [Date](#) [Cited by](#) [...](#)
[Export all](#) | [Add all to list](#) | [Set document alert](#) | [Set document feed](#)

Correlated Effects on Forming and Retention of Al Doping in HfO <sub>2</sub> -Based RRAM	Alayan, M., Vianello, E., De Salvo, B., (...), Padovani, A., Larcher, L.	2017	IEEE Design and Test	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
A microscopic mechanism of dielectric breakdown in SiO <sub>2</sub> films: An insight from multi-scale modeling	Padovani, A., Gao, D.Z., Shluger, A.L., Larcher, L.	2017	Journal of Applied Physics	1
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
Coexistence of Grain-Boundaries-Assisted Bipolar and Threshold Resistive Switching in Multilayer Hexagonal Boron Nitride	Pan, C., Ji, Y., Xiao, N., (...), Waser, R., Lanza, M.	2017	Advanced Functional Materials	1
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
2D h-BN based RRAM devices	Puglisi, F.M., Larcher, L., Pan, C., (...), Hui, F., Lanza, M.	2017	Technical Digest - International Electron Devices Meeting, IEDM	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
Multiscale modeling of electron-ion interactions for engineering novel electronic devices and materials	Larcher, L., Puglisi, F.M., Padovani, A., Vandelli, L., Pavan, P.	2017	Proceedings - 2016 26th International Workshop on Power and Timing Modeling, Optimization and Simulation, PATMOS 2016	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
Multiscale modeling of electron-ion interactions for engineering novel electronic device and materials	Larcher, L., Puglisi, F.M., Padovani, A., Vandelli, L., Pavan, P.	2017	Proceedings - 2016 26th International Workshop on Power and Timing Modeling, Optimization and Simulation, PATMOS 2016	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
Force impact effect in contact-mode triboelectric energy harvesters: Characterization and modeling	Lasagni, M., Pavan, P., Bertacchini, A., Larcher, L.	2017	Proceedings of IEEE Sensors	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
Infrared, transient thermal, and electrical properties of silver nanowire thin films for transparent heaters and energy-efficient coatings	Bobinger, M., Angeli, D., Colasanti, S., (...), Larcher, L., Lugli, P.	2017	Physica Status Solidi (A) Applications and Materials Science	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			
System with RF power delivery capabilities for active safety enhancement in industrial vehicles using interchangeable implements	Bertacchini, A., Napoletano, G., Scorcioni, S., Larcher, L., Pavan, P.	2016	IEEE Transactions on Intelligent Transportation Systems	0
View at Publisher	<a href="#">Find it</a> <a href="#">NTU</a>			

Follow this Author

Receive emails when this author publishes new articles

[Get citation alerts](#)
[Add to ORCID](#)
[Request author detail corrections](#)
[Export profile to SciVal](#)


## Author History

Publication range: 1998 - Present

 References: **2453**
**Source history:**
[IEEE Design and Test](#)
[View docu](#)

Proceedings of the 2012 International Conference on

Electromagnetics in Advanced Applications, ICEAA'12

[View docu](#)

2016 International Symposium on VLSI Technology, Syst

and Application, VLSI-TSA 2016

[View docu](#)
[View More](#)
[Show Related Affiliations](#)

Characterization and modeling of the thermal and electrical properties of transparent silver nanowire thin-film heaters	Bobinger, M., Colasanti, S., Lugli, P., (...), La Torraca, P., Larcher, L.	2016	16th International Conference on Nanotechnology - IEEE NANO 2016	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Anomalous random telegraph noise and temporary phenomena in resistive random access memory	Puglisi, F.M., Larcher, L., Padovani, A., Pavan, P.	2016	Solid-State Electronics	1
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Probing defects generation during stress in high-k/metal gate FinFETs by random telegraph noise characterization	Puglisi, F.M., Costantini, F., Kaczer, B., Larcher, L., Pavan, P.	2016	European Solid-State Device Research Conference	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Extraction of the Defect Distributions in DRAM Capacitor Using I-V and C-V Sensitivity Maps	Sereni, G., Larcher, L., Kaczer, B., Popovici, M.I.	2016	IEEE Electron Device Letters	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Random telegraph noise in HfO <sub>x</sub> Resistive Random Access Memory: From physics to compact modeling	Puglisi, F.M., Pavan, P., Larcher, L.	2016	IEEE International Reliability Physics Symposium Proceedings	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Root cause of degradation in novel HfO <sub>2</sub> -based ferroelectric memories	Pesic, M., Fengler, F.P.G., Slesazek, S., (...), Larcher, L., Padovani, A.	2016	IEEE International Reliability Physics Symposium Proceedings	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Nanoscale homogeneity and degradation process of two dimensional atomically thin hexagonal boron nitride dielectric stacks	Ji, Y., Pan, C., Hui, F., (...), Larcher, L., Lanza, M.	2016	Proceedings of the International Symposium on the Physical and Failure Analysis of Integrated Circuits, IPFA	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Monitoring Stress-Induced Defects in HK/MG FinFETs Using Random Telegraph Noise	Puglisi, F.M., Costantini, F., Kaczer, B., Larcher, L., Pavan, P.	2016	IEEE Electron Device Letters	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Physical Mechanisms behind the Field-Cycling Behavior of HfO <sub>2</sub> -Based Ferroelectric Capacitors	Pešić, M., Fengler, F.P.G., Larcher, L., (...), Schroeder, U., Mikolajick, T.	2016	Advanced Functional Materials	18
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Bipolar Resistive RAM Based on HfO <sub>2</sub> : Physics, Compact Modeling, and Variability Control	Puglisi, F.M., Larcher, L., Padovani, A., Pavan, P.	2016	IEEE Journal on Emerging and Selected Topics in Circuits and Systems	2
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				
Electrical defect spectroscopy and reliability prediction through a novel simulation-based methodology	Larcher, L., Sereni, G., Padovani, A., Vandelli, L.	2016	2016 International Symposium on VLSI Technology, Systems and Application, VLSI-TSA 2016	0
View at Publisher <a href="#">Find it</a> <a href="#">NTU</a>				

Display:  results per page

Page 1

[Back to results](#) | 1 of 1[Top of page](#)

The data displayed above is compiled exclusively from articles published in the Scopus database. To request corrections to any inaccuracies or provide any further feedback, please [contact us](#) (registration required). The data displayed above is subject to the privacy conditions contained in the [privacy policy](#).

## About Scopus

[What is Scopus](#)  
[Content coverage](#)  
[Scopus blog](#)  
[Scopus API](#)  
[Privacy matters](#)

## Language

[日本語に切り替える](#)  
[切换到简体中文](#)  
[切换到繁體中文](#)

## Customer service

[Help](#)  
[Contact us](#)

---

**ELSEVIER**[Terms and conditions](#)[Privacy policy](#)

Copyright © 2017 [Elsevier B.V.](#) All rights reserved. Scopus® is a registered trademark of Elsevier B.V.  
Cookies are set by this site. To decline them or learn more, visit our [Cookies page](#).

 RELX Group